

N-channel 30 V, 4.0 mΩ logic level MOSFET in LFPAK56 using NextPowerS3 Technology

10 October 2013

Product data sheet

1. General description

Logic level gate drive N-channel enhancement mode MOSFET in LFPAK56 package. NextPowerS3 portfolio utilising NXP's unique "SchottkyPlus" technology delivers high efficiency, low spiking performance usually associated with MOSFETs with an integrated Schottky or Schottky-like diode but without problematic high leakage current. NextPowerS3 is particularly suited to high efficiency applications at high switching frequencies.

2. Features and benefits

- Ultra low Q_G, Q_{GD} and Q_{OSS} for high system efficiency, especially at higher switching frequencies
- Superfast switching with soft-recovery; s-factor > 1
- Low spiking and ringing for low EMI designs
- Unique "SchottkyPlus" technology; Schottky-like performance with < 1 µA leakage at 25 °C
- Optimised for 4.5 V gate drive
- Low parasitic inductance and resistance
- High reliability clip bonded and solder die attach Power SO8 package; no glue, no wire bonds, qualified to 175 °C
- Wave solderable; exposed leads for optimal visual solder inspection

3. Applications

- On-board DC-to-DC solutions for server and telecommunications
- Secondary-side synchronous rectification in telecommunication applications
- Voltage regulator modules (VRM)
- Point-of-Load (POL) modules
- Power delivery for V-core, ASIC, DDR, GPU, VGA and system components
- Brushed and brushless motor control

4. Quick reference data

Table 1. Qui	ck reference data					
Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
V _{DS}	drain-source voltage	25 °C ≤ T _j ≤ 175 °C	-	-	30	V
I _D	drain current	T _{mb} = 25 °C; V _{GS} = 10 V; <u>Fig. 1</u>	-	-	95	А
P _{tot}	total power dissipation	T _{mb} = 25 °C; <u>Fig. 2</u>	-	-	64	W





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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Tj	junction temperature		-55	-	175	°C
Static charac	teristics	· · · · · ·		1	1	
R _{DSon}	drain-source on-state resistance	V _{GS} = 4.5 V; I _D = 25 A; T _j = 25 °C; <u>Fig. 10</u>	-	4.4	5.5	mΩ
		V _{GS} = 10 V; I _D = 25 A; T _j = 25 °C; <u>Fig. 10</u>	-	3.4	4	mΩ
Dynamic cha	racteristics				1	
Q _{GD}	gate-drain charge	V _{GS} = 4.5 V; I _D = 25 A; V _{DS} = 15 V; Fig. 12; Fig. 13	-	2.4	-	nC
Q _{G(tot)}	total gate charge	V _{GS} = 4.5 V; I _D = 25 A; V _{DS} = 15 V; Fig. 12; Fig. 13	-	9.1	-	nC
Source-drain	diode					
S	softness factor	$I_{S} = 25 \text{ A}; \text{ V}_{GS} = 0 \text{ V}; \text{ d}_{S}/\text{d}t = -100 \text{ A}/\mu\text{s};$ $\text{V}_{DS} = 15 \text{ V}; \text{ Fig. 16}$	-	1.1	-	

5. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	S	source	mb	D
2	S	source		
3	S	source	q	G L F A
4	G	gate	មុប្បូប្	mbb076 S
mb	D	mounting base; connected to drain	1 2 3 4 LFPAK56; Power- SO8 (SOT669)	

6. Ordering information

Table 3. Ordering in	Fable 3. Ordering information							
Type number	Package							
	Name	Description	Version					
PSMN4R0-30YLD	LFPAK56; Power-SO8	Plastic single-ended surface-mounted package (LFPAK56; Power-SO8); 4 leads	SOT669					

7. Marking

Table 4. Marking codes		
Type number	Marking code	
PSMN4R0-30YLD	4D030L	
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8. Limiting values

Table 5.Limiting values

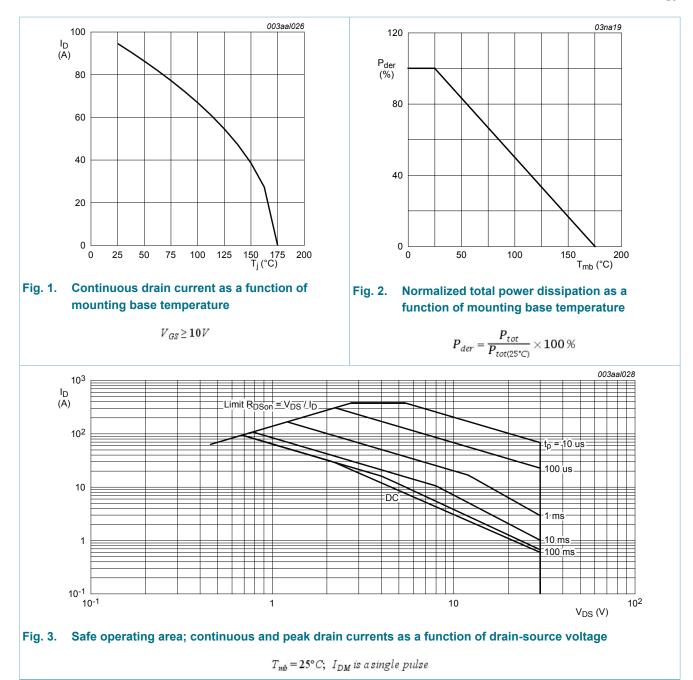
In accordance with the Absolute Maximum Rating System (IEC 60134).

Parameter	Conditions		Min	Max	Unit
drain-source voltage	25 °C ≤ T _j ≤ 175 °C		-	30	V
drain-gate voltage	25 °C ≤ T _j ≤ 175 °C; R _{GS} = 20 kΩ		-	30	V
gate-source voltage			-20	20	V
drain current	V _{GS} = 10 V; T _{mb} = 25 °C; <u>Fig. 1</u>		-	95	Α
	V _{GS} = 10 V; T _{mb} = 100 °C; <u>Fig. 1</u>		-	67	Α
peak drain current	pulsed; $t_p \le 10 \ \mu s$; $T_{mb} = 25 \ ^{\circ}C$; Fig. 3		-	378	Α
total power dissipation	T _{mb} = 25 °C; <u>Fig. 2</u>		-	64	W
storage temperature			-55	175	°C
junction temperature			-55	175	°C
peak soldering temperature			-	260	°C
electrostatic discharge voltage	НВМ		375	-	V
n diode	·	_	- 1		
source current	T _{mb} = 25 °C		-	54	Α
peak source current	pulsed; $t_p \le 10 \ \mu s$; $T_{mb} = 25 \ ^{\circ}C$		-	378	Α
ruggedness	·				
non-repetitive drain-source avalanche energy	V_{GS} = 10 V; $T_{j(init)}$ = 25 °C; I_D = 25 A; $V_{sup} \le 30$ V; R_{GS} = 50 Ω; unclamped; t_p = 129 µs	[1]	-	63	mJ
	drain-source voltage drain-gate voltage gate-source voltage gate-source voltage drain current peak drain current total power dissipation storage temperature junction temperature peak soldering temperature electrostatic discharge voltage ndiode source current peak source current non-repetitive drain-source	$\begin{tabular}{ c $	$\begin{array}{ c c c } \hline drain-source voltage & 25 \ ^{\circ}C \leq T_{j} \leq 175 \ ^{\circ}C & \\ \hline drain-gate voltage & 25 \ ^{\circ}C \leq T_{j} \leq 175 \ ^{\circ}C; \ R_{GS} = 20 \ k\Omega & \\ \hline gate-source voltage & & \\ \hline drain current & V_{GS} = 10 \ V; \ T_{mb} = 25 \ ^{\circ}C; \ Fig. 1 & \\ \hline V_{GS} = 10 \ V; \ T_{mb} = 100 \ ^{\circ}C; \ Fig. 1 & \\ \hline V_{GS} = 10 \ V; \ T_{mb} = 100 \ ^{\circ}C; \ Fig. 1 & \\ \hline V_{GS} = 10 \ V; \ T_{mb} = 25 \ ^{\circ}C; \ Fig. 3 & \\ \hline total power dissipation & T_{mb} = 25 \ ^{\circ}C; \ Fig. 2 & \\ \hline total power dissipation & T_{mb} = 25 \ ^{\circ}C; \ Fig. 2 & \\ \hline total power dissipation & \hline T_{mb} = 25 \ ^{\circ}C; \ Fig. 2 & \\ \hline total power dissipation & \hline T_{mb} = 25 \ ^{\circ}C; \ Fig. 2 & \\ \hline total power dissipation & T_{mb} = 25 \ ^{\circ}C; \ Fig. 2 & \\ \hline total power dissipation & \hline T_{mb} = 25 \ ^{\circ}C; \ Fig. 2 & \\ \hline total power dissipation & \hline T_{mb} = 25 \ ^{\circ}C; \ Fig. 2 & \\ \hline total power dissipation & \hline T_{mb} = 25 \ ^{\circ}C; \ Fig. 2 & \\ \hline peak soldering temperature & & \\ \hline total power discharge voltage & HBM & \\ \hline total box & \hline total box & \\ \hline total box & \hline total box & \\ \hline total box & \hline total box & \\ \hline total power discharge voltage & T_{mb} = 25 \ ^{\circ}C & \\ \hline peak source current & T_{mb} = 25 \ ^{\circ}C & \\ \hline peak source current & pulsed; \ t_{p} \leq 10 \ \mu s; \ T_{mb} = 25 \ ^{\circ}C & \\ \hline total power discharge voltage & \\ \hline total box $	drain-source voltage25 °C ≤ Tj ≤ 175 °C-drain-gate voltage25 °C ≤ Tj ≤ 175 °C; RGS = 20 kΩ-gate-source voltage25 °C ≤ Tj ≤ 175 °C; RGS = 20 kΩ-drain currentVGS = 10 V; Tmb = 25 °C; Fig. 1- V_{GS} = 10 V; Tmb = 25 °C; Fig. 1-peak drain currentpulsed; tp ≤ 10 µs; Tmb = 25 °C; Fig. 3-total power dissipationTmb = 25 °C; Fig. 2-storage temperature-55junction temperature-55peak soldering temperature-electrostatic discharge voltageHBM375non-repetitive drain-sourceVGS = 10 V; Tj(init) = 25 °C; ID = 25 A; Vsup ≤ 30 V; RGS = 50 Ω; unclamped;[1]	drain-source voltage25 °C ≤ Tj ≤ 175 °C<

[1] Protected by 100% test

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9. Thermal characteristics

Table 6. The	rmal characteristics					
Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base	Fig. 6	-	2.14	2.33	K/W

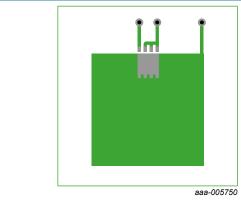
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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
R _{th(j-a)}	thermal resistance	Fig. 4	-	50	-	K/W
	from junction to ambient	<u>Fig. 5</u>	-	125	-	K/W



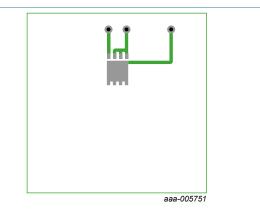


Fig. 4. PCB layout for thermal resistance junction to ambient 1" square pad; FR4 Board; 2oz copper



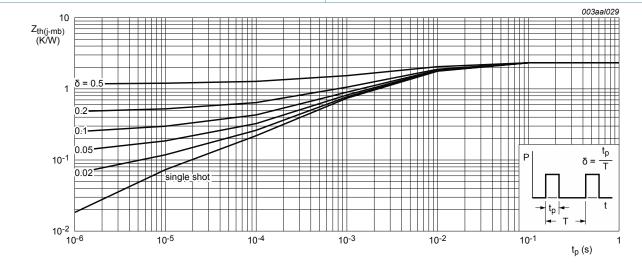


Fig. 6. Transient thermal impedance from junction to mounting base as a function of pulse duration

10. Characteristics

Table 7. C	haracteristics					
Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static chara	octeristics	· · · · ·	l.			
V _{(BR)DSS} drain-source	I_D = 250 µA; V_{GS} = 0 V; T_j = 25 °C	30	-	-	V	
	breakdown voltage	I_D = 250 µA; V_{GS} = 0 V; T_j = -55 °C	27	-	-	V
V _{GS(th)}	gate-source threshold voltage	I_D = 1 mA; V_{DS} = V_{GS} ; T_j = 25 °C	1.2	1.74	2.2	V

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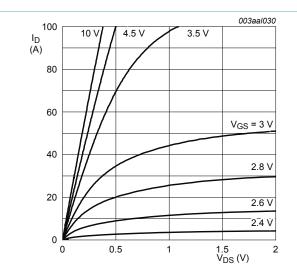
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Symbol	Parameter	Conditions	Min	Тур	Max	Unit
ΔV _{GS(th)} /ΔT	gate-source threshold voltage variation with temperature	25 °C < T _j < 150 °C	-	-4.1	-	mV/K
I _{DSS}	drain leakage current	V_{DS} = 24 V; V_{GS} = 0 V; T_j = 25 °C	-	-	1	μA
		V _{DS} = 24 V; V _{GS} = 0 V; T _j = 150 °C	-	-	100	μA
I _{GSS}	gate leakage current	V _{GS} = 16 V; V _{DS} = 0 V; T _j = 25 °C	-	-	100	nA
		V_{GS} = -16 V; V_{DS} = 0 V; T_j = 25 °C	-	-	100	nA
R _{DSon}	drain-source on-state resistance	V _{GS} = 4.5 V; I _D = 25 A; T _j = 25 °C; <u>Fig. 10</u>	-	4.4	5.5	mΩ
		V _{GS} = 4.5 V; I _D = 25 A; T _j = 150 °C; Fig. 11; Fig. 10	-	-	9.1	mΩ
		V _{GS} = 10 V; I _D = 25 A; T _j = 25 °C; Fig. 10	-	3.4	4	mΩ
		V _{GS} = 10 V; I _D = 25 A; T _j = 150 °C; Fig. 11; Fig. 10	-	-	6.6	mΩ
R _G	gate resistance	f = 1 MHz	-	2.2	-	Ω
Dynamic cha	aracteristics		I			
Q _{G(tot)}	total gate charge	I _D = 25 A; V _{DS} = 15 V; V _{GS} = 10 V; Fig. 12; Fig. 13	-	19.4	-	nC
		I_D = 25 A; V_{DS} = 15 V; V_{GS} = 4.5 V; Fig. 12; Fig. 13	-	9.1	-	nC
		$I_D = 0 A; V_{DS} = 0 V; V_{GS} = 10 V$	-	18.2	-	nC
Q _{GS}	gate-source charge	I_D = 25 A; V_{DS} = 15 V; V_{GS} = 4.5 V;	-	2.6	-	nC
Q _{GS(th)}	pre-threshold gate- source charge	Fig. 12; Fig. 13	-	1.9	-	nC
Q _{GS(th-pl)}	post-threshold gate- source charge		-	0.7	-	nC
Q _{GD}	gate-drain charge		-	2.4	-	nC
V _{GS(pl)}	gate-source plateau voltage	I _D = 25 A; V _{DS} = 15 V; <u>Fig. 12</u> ; <u>Fig. 13</u>	-	2.3	-	V
C _{iss}	input capacitance	V _{DS} = 15 V; V _{GS} = 0 V; f = 1 MHz;	-	1272	-	pF
C _{oss}	output capacitance	T _j = 25 °C; <u>Fig. 14</u>	-	812	-	pF
C _{rss}	reverse transfer capacitance		-	87	-	pF
t _{d(on)}	turn-on delay time	V_{DS} = 15 V; R _L = 0.6 Ω; V _{GS} = 4.5 V;	-	10.7	-	ns
t _r	rise time	$R_{G(ext)} = 5 \Omega$	-	21.2	-	ns
t _{d(off)}	turn-off delay time		-	14.9	-	ns
		-				-

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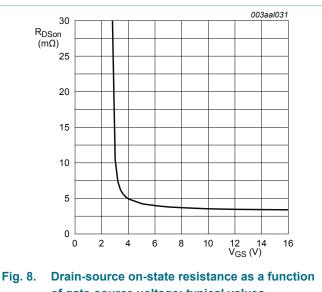
Symbol	Parameter	Conditions		Min	Тур	Max	Unit
Q _{oss}	output charge	V _{GS} = 0 V; V _{DS} = 15 V; f = 1 MHz; T _j = 25 °C		-	16	-	nC
Source-dra	in diode	·					
V _{SD}	source-drain voltage	I_{S} = 15 A; V_{GS} = 0 V; T_{j} = 25 °C; <u>Fig. 15</u>		-	0.82	1.2	V
t _{rr}	reverse recovery time	I_{S} = 25 A; dI_{S}/dt = -100 A/µs; V_{GS} = 0 V;		-	25.1	-	ns
Q _r	recovered charge	V _{DS} = 15 V; <u>Fig. 16</u>	[1]	-	13.3	-	nC
t _a	reverse recovery rise time			-	11.9	-	ns
t _b	reverse recovery fall time			-	13.1	-	ns
S	softness factor			-	1.1	-	



[1] includes capacitive recovery



 $T_j = 25^{\circ}C$

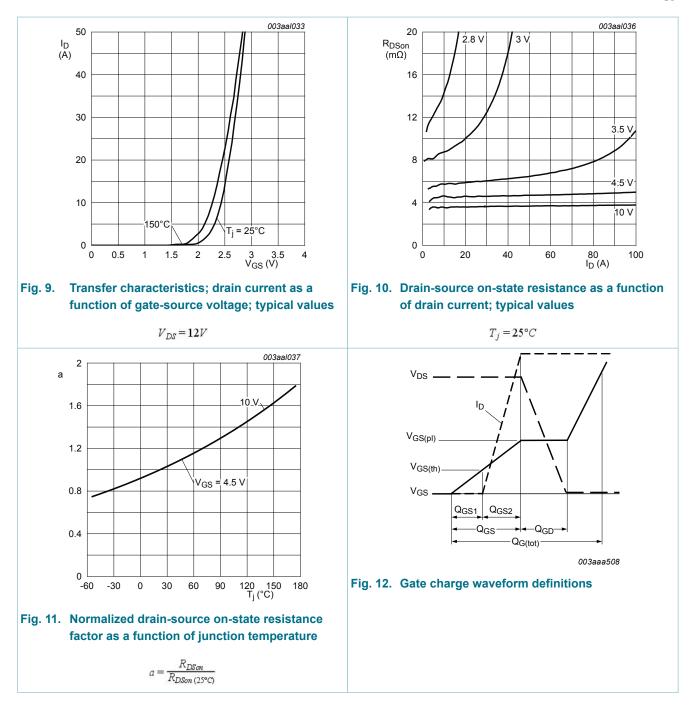


of gate-source voltage; typical values

 $T_j = 25^{\circ}C; \ I_D = 25A$

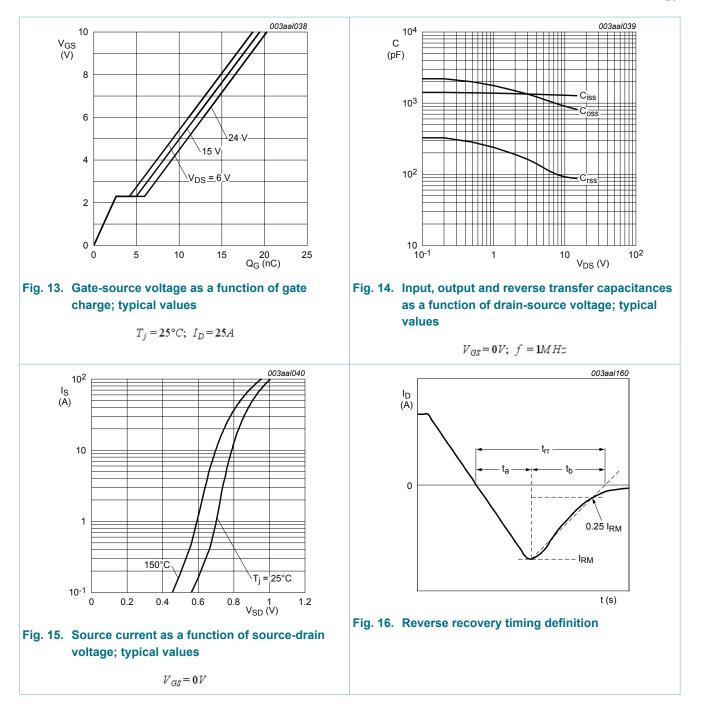
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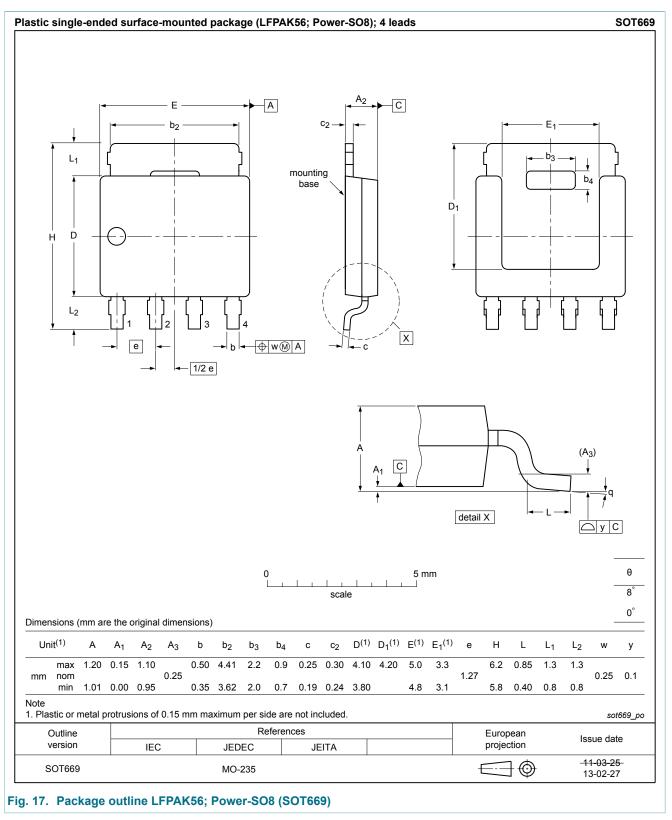
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11. Package outline



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12. Legal information

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Document status [1][2]	Product status [<u>3]</u>	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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	General description Features and benefits

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